

Normally – OFF Silicon Carbide Junction Transistor

Features

- 175 °C Maximum Operating Temperature
- Gate Oxide Free SiC Switch
- Exceptional Safe Operating Area
- Excellent Gain Linearity
- Temperature Independent Switching Performance

• Compatible with Si MOSFET/IGBT Gate Drive ICs

• Low Output Capacitance

Advantages

High Circuit EfficiencyMinimal Input Signal Distortion

• High Amplifier Bandwidth

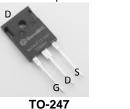
• Positive Temperature Coefficient of $\mathsf{R}_{\mathsf{DS},\mathsf{ON}}$

• > 20 µs Short-Circuit Withstand Capability

• Lowest-in-class Conduction Losses

• Suitable for Connecting an Anti-parallel Diode

Package RoHS Compliant





Applications

• Down Hole Oil Drilling, Geothermal Instrumentation

 V_{DS}

R_{DS(ON)}

 I_D (Tc = 25°C)

L (Tc > 125°C)

h_{FE (Tc = 25°C)}

- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

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Section I: Absolute Maximum Ratings

| Parameter | Symbol | Conditions | Value | Unit | Notes |
|-----------------------------------|------------------|---|---|------|---------|
| Drain – Source Voltage | V _{DS} | $V_{GS} = 0 V$ | 1200 | V | |
| Continuous Drain Current | Ι _D | $T_{\rm C} = 25^{\circ}{\rm C}$ | 25 | А | Fig. 17 |
| Continuous Drain Current | ID | T _C = 155°C | 10 | А | Fig. 17 |
| Continuous Gate Current | l _G | | 1.3 | А | |
| Turn-Off Safe Operating Area | RBSOA | T _{VJ} = 175 °C, Clamped Inductive Load | I _{D,max} = 10 @ V _{DS} ≤ V _{DSmax} | А | Fig. 19 |
| Short Circuit Safe Operating Area | SCSOA | $T_{VJ} = 175 \ ^{\circ}C$, $I_G = 1 \ A$, $V_{DS} = 800 \ V$, Non Repetitive | >20 | μs | |
| Reverse Gate – Source Voltage | V_{SG} | | 30 | V | |
| Reverse Drain – Source Voltage | V _{SD} | | 25 | V | |
| Power Dissipation | P _{tot} | $T_{C} = 25 \text{ °C} / 155 \text{ °C}, t_{p} > 100 \text{ ms}$ | 170 / 22 | W | Fig. 16 |
| Storage Temperature | T _{stg} | | -55 to 175 | °C | |

Jan 2015

GA10JT12-247

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1200 V

100 mΩ

25 A

10 A

98

GA10JT12-247

Section II: Static Electrical Characteristics

| Demonster | Cumula al | Conditions | | Value | | 11 | | |
|-------------------------------------|--|--|---|-------------------|-------------------|------|---------|--------|
| Parameter | Symbol | Conditions | Min. | Typical | Max. | Unit | Notes | |
| A: On State | | | | | | | | |
| Drain – Source On Resistance | $ \begin{array}{l} I_{D} = 10 \text{ A}, \ T_{j} = 25 \ ^{\circ}\text{C} \\ R_{DS(ON)} & I_{D} = 10 \text{ A}, \ T_{j} = 150 \ ^{\circ}\text{C} \\ I_{D} = 10 \text{ A}, \ T_{i} = 175 \ ^{\circ}\text{C} \end{array} $ | | ain – Source On Resistance $R_{DS(ON)}$ $I_D = 10 \text{ A}, T_j = 150$ | | 100 160 180 | | mΩ | Fig. 4 |
| Gate – Source Saturation Voltage | $V_{\text{GS},\text{SAT}}$ | L = 10 A L/L = 40 T = 25 °C | | 3.50 3.27 | | V | Fig. 7 | |
| DC Current Gain | $ \begin{array}{l} V_{DS} = 8 \ V, \ I_D = 10 \ A, \ T_i = 25 \ ^{\circ}\text{C} \\ N_{DS} = 8 \ V, \ I_D = 10 \ A, \ T_i = 125 \ ^{\circ}\text{C} \\ V_{DS} = 8 \ V, \ I_D = 10 \ A, \ T_i = 175 \ ^{\circ}\text{C} \end{array} $ | | | 98 65 58 | | _ | Fig. 5 | |
| B: Off State | | | | | | | | |
| Drain Leakage Current | I _{DSS} | | | 0.1 0.1 0.1 | | μA | Fig. 8 | |
| Gate Leakage Current | I _{SG} | $V_{SG} = 20 \text{ V}, \text{ T}_{j} = 25 \text{ °C}$ | | 20 | | nA | | |
| C: Thermal | | | | | | | | |
| Thermal resistance, junction - case | R _{thJC} | | | 0.88 | | °C/W | Fig. 20 | |

Section III: Dynamic Electrical Characteristics

| Devenenter | Symbol Conditions | | Value | | | 11 | Natas | |
|--|--------------------------|--|-------|-------------------|--|------|------------|--|
| Parameter | Symbol | Conditions | Min. | Min. Typical Max. | | Unit | Notes | |
| A: Capacitance and Gate Charge | е | | | | | | | |
| nput Capacitance | C _{iss} | V _{GS} = 0 V, V _{DS} = 800 V, <i>f</i> = 1 MHz | | 1403 | | pF | Fig. 9 | |
| Reverse Transfer/Output Capacitance | Crss/Coss | V _{DS} = 800 V, <i>f</i> = 1 MHz | | 30 | | pF | Fig. 9 | |
| Dutput Capacitance Stored Energy | Eoss | V _{GS} = 0 V, V _{DS} = 800 V, <i>f</i> = 1 MHz | | 13 | | μJ | Fig. 10 | |
| Effective Output Capacitance, ime related | C _{oss,tr} | I_{D} = constant, V_{GS} = 0 V, V_{DS} = 0…800 V | | 55 | | pF | | |
| Effective Output Capacitance, energy related | $C_{\text{oss,er}}$ | V_{GS} = 0 V, V_{DS} = 0800 V | | 40 | | pF | | |
| Gate-Source Charge | Q _{GS} | V _{GS} = -53 V | | 11 | | nC | | |
| Gate-Drain Charge | Q _{GD} | V _{GS} = 0 V, V _{DS} = 0800 V | | 44 | | nC | | |
| Gate Charge - Total | Q_{G} | | | 55 | | nC | | |
| B: Switching ¹ | | | | | | | | |
| nternal Gate Resistance – zero bias | R _{G(INT-ZERO)} | f = 1 MHz, V _{AC} = 50 mV, V _{DS} = 0 V, V _{GS} = 0 V, T _i = 175 °C | | 2.6 | | Ω | | |
| nternal Gate Resistance – ON | R _{G(INT-ON)} | V _{GS} > 2.5 V, V _{DS} = 0 V, T _j = 175 °C | | 0.19 | | Ω | | |
| Furn On Delay Time | t _{d(on)} | $T_i = 25 ^{\circ}C, V_{DS} = 800 V,$ | | 10 | | ns | | |
| Fall Time, V _{DS} | t _f | $I_{\rm D} = 10$ A, Resistive Load | | 9 | | ns | Fig. 11, 1 | |
| Turn Off Delay Time t _{d(} | | Refer to Section V for additional | | 22 | | ns | | |
| Rise Time, V _{DS} | tr | driving information. | | 9 | | ns | Fig. 12, 1 | |
| Γurn On Delay Time | t _{d(on)} | | | 9 | | ns | | |
| Fall Time, V _{DS} | t _f | T _i = 175 °C, V _{DS} = 800 V, | | 8 | | ns | Fig. 11 | |
| Furn Off Delay Time | t _{d(off)} | I _D = 10 A, Resistive Load | | 35 | | ns | | |
| Rise Time, V _{DS} | tr | | | 9 | | ns | Fig. 12 | |
| Turn-On Energy Per Pulse | Eon | | | 142 | | μJ | Fig. 11, 1 | |
| Furn-Off Energy Per Pulse | E _{off} | $I_D = 10 \text{ A}$, Inductive Load | | 7 | | μJ | Fig. 12, 1 | |
| Total Switching Energy | 0, | | | 149 | | μJ | - | |
| Furn-On Energy Per Pulse | Eon | T (TT 00)/ 000)/ | | 142 | | μJ | Fig. 11 | |
| Furn-Off Energy Per Pulse | E _{off} | $-T_{j} = 175 ^{\circ}C, V_{DS} = 800 V,$ $-I_{D} = 10 A, Inductive Load$ | | 6 | | μJ | Fig. 12 | |
| Total Switching Energy E_{tot} | | -10 = 10 A, inductive L0du | | 148 | | μJ | | |

 1 – All times are relative to the Drain-Source Voltage V_{DS}

E_{tot}

Total Switching Energy

μJ

GA10JT12-247

Section IV: Figures

A: Static Characteristic Figures

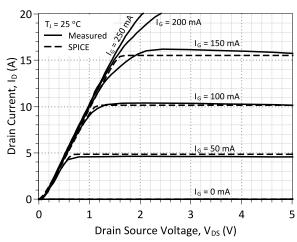


Figure 1: Typical Output Characteristics at 25 °C

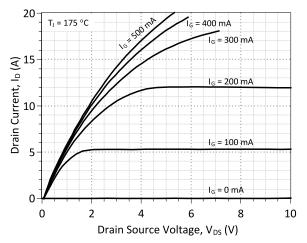


Figure 3: Typical Output Characteristics at 175 °C

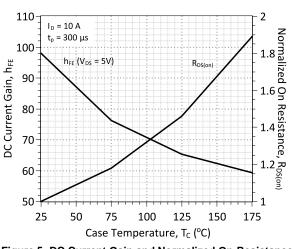


Figure 5: DC Current Gain and Normalized On-Resistance vs. Temperature

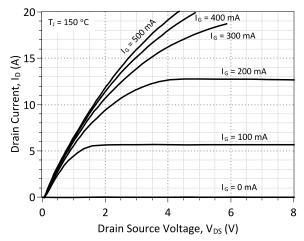


Figure 2: Typical Output Characteristics at 150 °C

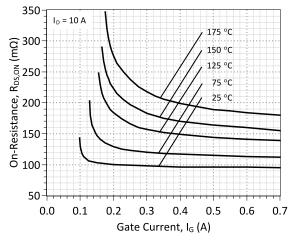


Figure 4: On-Resistance vs. Gate Current

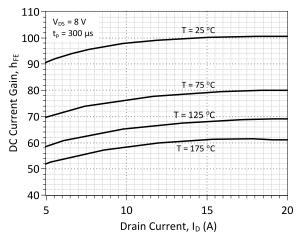


Figure 6: DC Current Gain vs. Drain Current

GA10JT12-247

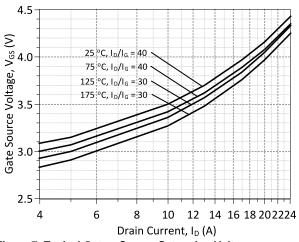


Figure 7: Typical Gate – Source Saturation Voltage



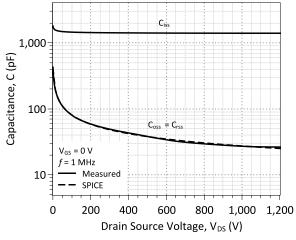


Figure 9: Input, Output, and Reverse Transfer Capacitance

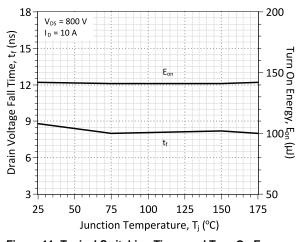


Figure 11: Typical Switching Times and Turn On Energy Losses vs. Temperature

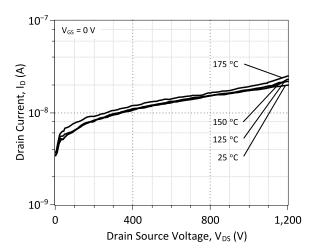


Figure 8: Typical Blocking Characteristics

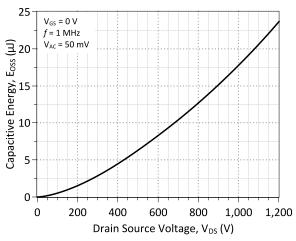


Figure 10: Energy Stored in Output Capacitance

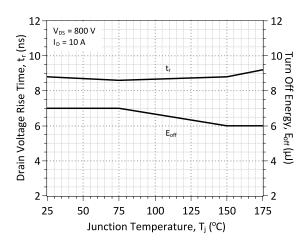


Figure 12: Typical Switching Times and Turn Off Energy Losses vs. Temperature

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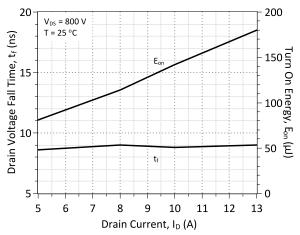


Figure 13: Typical Switching Times and Turn On Energy Losses vs. Drain Current

C: Device Derating Figures

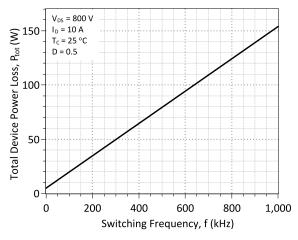


Figure 15: Typical Hard Switched Device Power Loss vs. Switching Frequency²

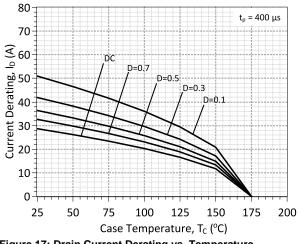


Figure 17: Drain Current Derating vs. Temperature

GA10JT12-247

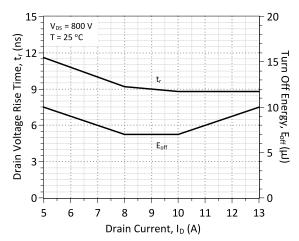
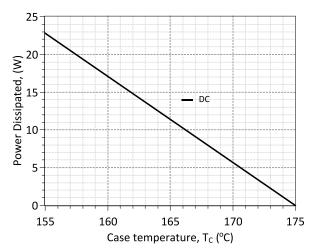
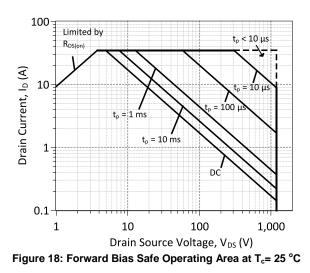


Figure 14: Typical Switching Times and Turn Off Energy Losses vs. Drain Current

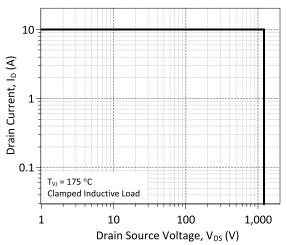






² – Representative values based on device conduction and switching loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.





TOR

Figure 19: Turn-Off Safe Operating Area

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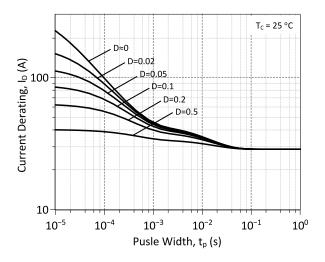


Figure 21: Drain Current Derating vs. Pulse Width

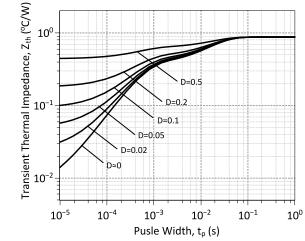


Figure 20: Transient Thermal Impedance



Section V: Driving the GA10JT12-247

| Drive Topology | Gate Drive Power Swit Consumption Freq | | Application Emphasis | Availability |
|------------------------------|---|--------|--------------------------|--------------|
| TTL Logic | High | Low | Wide Temperature Range | Coming Soon |
| Constant Current | Medium | Medium | Wide Temperature Range | Coming Soon |
| High Speed – Boost Capacitor | Medium | High | Fast Switching | Production |
| High Speed – Boost Inductor | Low | High | Ultra Fast Switching | Coming Soon |
| Proportional | Lowest | High | Wide Drain Current Range | Coming Soon |
| Pulsed Power | Medium | N/A | Pulse Power | Coming Soon |

A: Static TTL Logic Driving

The GA10JT12-247 may be driven using direct (5 V) TTL logic after current amplification. The (amplified) current level of the supply must meet or exceed the steady state gate current ($I_{G,steady}$) required to operate the GA10JT12-247. The power level of the supply can be estimated from the target duty cycle of the particular application. $I_{G,steady}$ is dependent on the anticipated drain current ID through the SJT and the DC current gain $h_{FE,}$ it may be calculated from the following equation. An accurate value of the h_{FE} may be read from Figure 6.

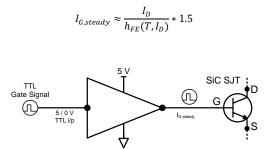


Figure 22: TTL Gate Drive Schematic

B: High Speed Driving

The SJT is a current controlled transistor which requires a positive gate current for turn-on as well as to remain in on-state. An ideal gate current waveform for ultra-fast switching of the SJT, while maintaining low gate drive losses, is shown in Figure 23 which features a positive current peak during turn-on, a negative current peak during turn-off, and continuous gate current to remain on.

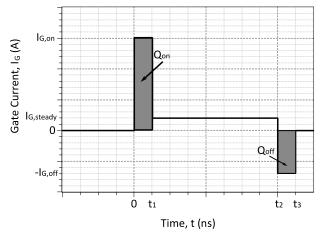


Figure 23: An idealized gate current waveform for fast switching of an SJT.

An SJT is rapidly switched from its blocking state to on-state, when the necessary gate charge, Q_G , for turn-on is supplied by a burst of high gate current, $I_{G,on}$, until the gate-source capacitance, C_{GS} , and gate-drain capacitance, C_{GD} , are fully charged.

$$Q_{on} = I_{G,on} * t_1$$
$$Q_{on} \ge Q_{gs} + Q_{gd}$$



GA10JT12-247

Ideally, $I_{G,pon}$ should terminate when the drain voltage falls to its on-state value in order to avoid unnecessary drive losses during the steady on-state. In practice, the rise time of the $I_{G,on}$ pulse is affected by the parasitic inductances, L_{par} in the device package and drive circuit. A voltage developed across the parasitic inductance in the source path, L_s , can de-bias the gate-source junction, when high drain currents begin to flow through the device. The voltage applied to the gate pin should be maintained high enough, above the $V_{GS,sat}$ (see**Error! Reference ource not found.**) level to counter these effects.

A high negative peak current, $-I_{G,off}$ is recommended at the start of the turn-off transition, in order to rapidly sweep out the injected carriers from the gate, and achieve rapid turn-off. While satisfactory turn off can be achieved with $V_{GS} = 0$ V, a negative gate voltage V_{GS} may be used in order to speed up the turn-off transition.

Two high-speed drive topologies for the SiC SJTs are presented below.

B:1: High Speed, Low Loss Drive with Boost Capacitor, GA03IDDJT30-FR4

The GA10JT12-247 may be driven using a High Speed, Low Loss Drive with Boost Capacitor topology in which multiple voltage levels, a gate resistor, and a gate capacitor are used to provide fast switching current peaks at turn-on and turn-off and a continuous gate current while in on-state. A 3 kV isolated evaluation gate drive board (GA03IDDJT30-FR4) utilizing this topology is commercially available for high and low-side driving, its datasheet provides additional details about this drive topology.

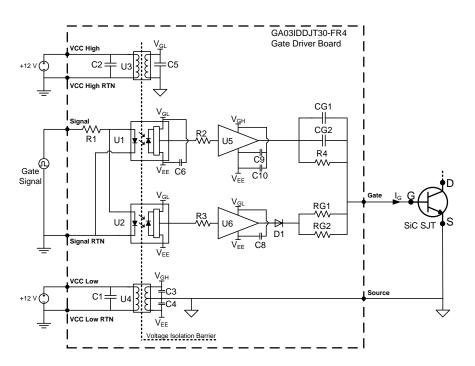


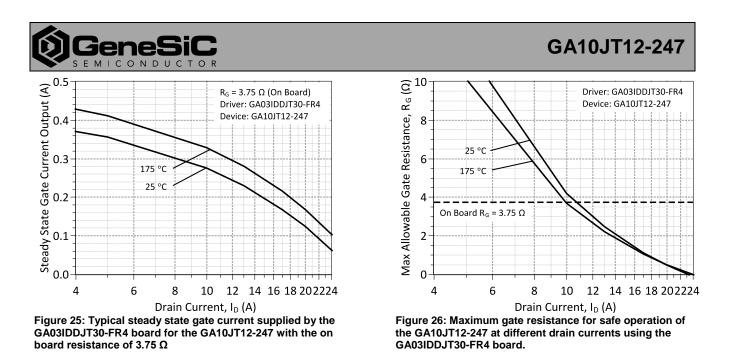
Figure 24: Topology of the GA03IDDJT30-FR4 Two Voltage Source gate driver.

The GA03IDDJT30-FR4 evaluation board comes equipped with two on board gate drive resistors (RG1, RG2) pre-installed for an effective gate resistance³ of R_G = 3.75 Ω . It may be necessary for the user to reduce RG1 and RG2 under high drain current conditions for safe operation of the GA10JT12-247. The steady state current supplied to the gate pin of the GA10JT12-247 with on-board R_G = 3.75 Ω , is shown in Figure 25. The maximum allowable safe value of R_G for the user's required drain current can be read from Figure 26.

For the GA10JT12-247, R_g must be reduced for $I_D \ge \sim 10$ A for safe operation with the GA03IDDJT30-FR4.

For operation at $I_D \ge \sim 10$ A, R_G may be calculated from the following equation, which contains the DC current gain h_{FE} (Figure 6) and the gate-source saturation voltage $V_{GS,sat}$ (Figure 7).

$$R_{G,max} = \frac{\left(4.7V - V_{GS,sat}\right) * h_{FE}(T, I_D)}{I_D * 1.5} - 0.6\Omega$$



B:2: High Speed, Low Loss Drive with Boost Inductor

A High Speed, Low-Loss Driver with Boost Inductor is also capable of driving the GA10JT12-247 at high-speed. It utilizes a gate drive inductor instead of a capacitor to provide the high-current gate current pulses $I_{G,on}$ and $I_{G,off}$. During operation, inductor L is charged to a specified $I_{G,on}$ current value then made to discharge I_L into the SJT gate pin using logic control of S_1 , S_2 , S_3 , and S_4 , as shown in Figure 27. After turn on, while the device remains on the necessary steady state gate current $I_{G,steady}$ is supplied from source VCC through RG. Please refer to the article "A current-source concept for fast and efficient driving of silicon carbide transistors" by Dr. Jacek Rąbkowski for additional information on this driving topology.⁴

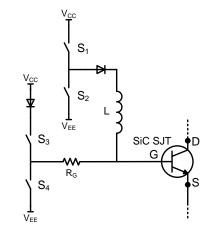


Figure 27: Simplified Inductive Pulsed Drive Topology

⁴ – Archives of Electrical Engineering. Volume 62, Issue 2, Pages 333–343, ISSN (Print) 0004-0746, DOI: 10.2478/aee-2013-0026, June 2013

 $^{^{3}}$ - R_G = (1/RG1 +1/RG2)⁻¹. Driver is pre-installed with RG1 = RG2 = 7.5 Ω



C: Proportional Gate Current Driving

For applications in which the GA10JT12-247 will operate over a wide range of drain current conditions, it may be beneficial to drive the device using a proportional gate drive topology to optimize gate drive power consumption. A proportional gate drive relies on instantaneous drain current I_D feedback to vary the steady state gate current $I_{G, steady}$ supplied to the GA10JT12-247

C:1: Voltage Controlled Proportional Driver

The voltage controlled proportional driver relies on a gate drive IC to detect the GA10JT12-247 drain-source voltage V_{DS} during on-state to sense I_D. The gate drive IC will then increase or decrease I_{G,steady} in response to I_D. This allows I_{G,steady}, and thus the gate drive power consumption, to be reduced while I_D is relatively low or for I_{G,steady} to increase when is I_D higher. A high voltage diode connected between the drain and sense protects the IC from high-voltage when the driver and GA10JT12-247 are in off-state. A simplified version of this topology is shown in Figure 29, additional information will be available in the future at http://www.genesicsemi.com/commercial-sic/sic-junction-transistors/

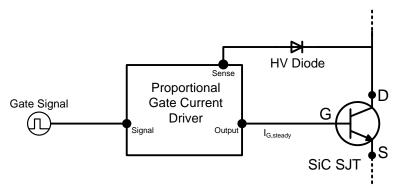


Figure 28: Simplified Voltage Controlled Proportional Driver

C:2: Current Controlled Proportional Driver

The current controlled proportional driver relies on a low-loss transformer in the drain or source path to provide feedback I_D of the GA10JT12-247 during on-state to supply $I_{G,steady}$ into the device gate. $I_{G,steady}$ will then increase or decrease in response to I_D at a fixed forced current gain which is set be the turns ratio of the transformer, $h_{force} = I_D / I_G = N_2 / N_1$. GA10JT12-247 is initially tuned-on using a gate current pulse supplied into an RC drive circuit to allow I_D current to begin flowing. This topology allows $I_{G,steady}$, and thus the gate drive power consumption, to be reduced while I_D is relatively low or for $I_{G,steady}$ to increase when is I_D higher. A simplified version of this topology is shown in Figure 29, additional information will be available in the future at http://www.genesicsemi.com/commercial-sic/sic-junction-transistors/.

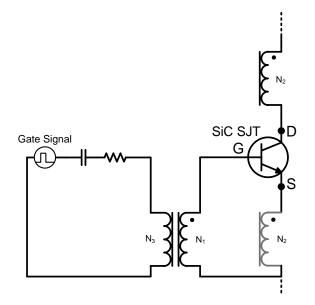
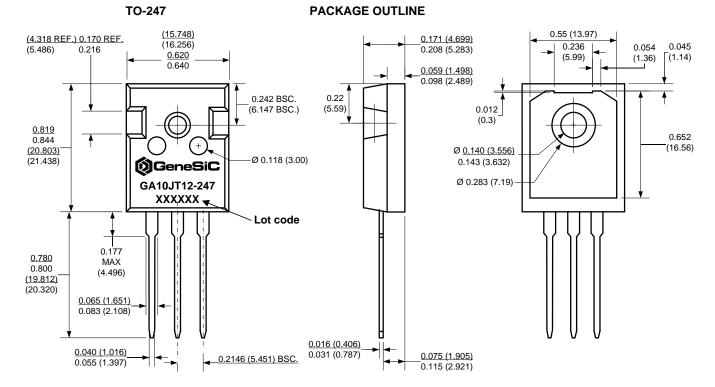


Figure 29: Simplified Current Controlled Proportional Driver



Section VII: Package Dimensions

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NOTE

1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.

2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

| Revision History | | | | | | | |
|------------------|----------|------------------------------------|------------|--|--|--|--|
| Date | Revision | Comments | Supersedes | | | | |
| 2015/01/28 | 2 | Updated Electrical Characteristics | | | | | |
| 2014/11/12 | 1 | Updated Electrical Characteristics | | | | | |
| 2014/08/25 | 0 | Initial release | | | | | |

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Section VIII: SPICE Model Parameters

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/products_sic/sjt/GA10JT12-247_SPICE.pdf) into LTSPICE (version 4) software for simulation of the GA10JT12-247.

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     $Revision:
*
                   2.1
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     $Date: 29-JAN-2015
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* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
.model GA10JT12 NPN
+ IS
           9.833E-48
+ ISE
           1.073E-26
+ EG
           3.23
+ BF
           113
+ BR
           0.55
           5000
+ IKF
+ NF
           1
+ NE
           2
+ RB
          4.67
+ IRB
           0.001
+ RBM
           0.16
+ RE
           0.005
+ RC
           0.083
+ CJC
           427.39E-12
+ VJC
           3.1004
+ MJC
           0.4752
           1373E-12
+ CJE
           10.6442
+ VJE
+ MJE
           0.21376
+ XTI
           3
           -1.35
+ XTB
           7E-3
+ TRC1
+ VCEO
           1200
+ ICRATING 10
+ MFG
           GeneSiC Semiconductor
* End of GA10JT12 SPICE Model
```